



SEMiX® 5

Trench IGBT Modules

Engineering Sample SEMiX305GD07E4

Target Data

Features

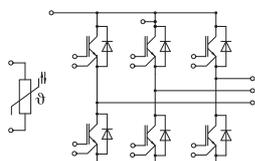
- Solderless assembly solution with PressFIT signal pins and screw power terminals
- IGBT 4 Trench Gate Technology
- $V_{CE(sat)}$ with positive temperature coefficient
- Low inductance case
- Reliable mechanical design with injection moulded terminals and robust internal connections
- UL recognized file no. E63532
- NTC temperature sensor inside

Typical Applications*

- Three phase inverters for AC motor speed control
- UPS

Remarks

- Case temperature limited to $T_C=125^\circ\text{C}$ max.
- Product reliability results are valid for $T_{jop}=150^\circ\text{C}$
- Dynamic data are estimated
- For storage and case temperature with TIM see document "TP(HALA P8) SEMiX 5p"



GD

Absolute Maximum Ratings

Symbol	Conditions	Values	Unit	
IGBT				
V_{CES}	$T_j = 25^\circ\text{C}$	650	V	
I_C	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	372	A
		$T_c = 80^\circ\text{C}$	281	A
I_{Cnom}		300	A	
I_{CRM}	$I_{CRM} = 3 \times I_{Cnom}$	900	A	
V_{GES}		-20 ... 20	V	
t_{psc}	$V_{CC} = 360\text{ V}$ $V_{GE} \leq 15\text{ V}$ $V_{CES} \leq 650\text{ V}$	$T_j = 150^\circ\text{C}$	10	μs
T_j		-40 ... 175	$^\circ\text{C}$	

Inverse diode

V_{RRM}	$T_j = 25^\circ\text{C}$	650	V	
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	335	A
		$T_c = 80^\circ\text{C}$	244	A
I_{Fnom}		300	A	
I_{FRM}	$I_{FRM} = 2 \times I_{Fnom}$	600	A	
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$	2160	A	
T_j		-40 ... 175	$^\circ\text{C}$	

Module

$I_{t(RMS)}$		400	A
T_{stg}	module without TIM	-40 ... 125	$^\circ\text{C}$
V_{isol}	AC sinus 50Hz, $t = 1\text{ min}$	4000	V

Characteristics

Symbol	Conditions	min.	typ.	max.	Unit
IGBT					
$V_{CE(sat)}$	$I_C = 300\text{ A}$ $V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$	1.55	1.95	V
		$T_j = 150^\circ\text{C}$	1.75	2.15	V
V_{CE0}	chipllevel	$T_j = 25^\circ\text{C}$	0.9	1	V
		$T_j = 150^\circ\text{C}$	0.82	0.9	V
r_{CE}	$V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$	2.2	3.2	$\text{m}\Omega$
		$T_j = 150^\circ\text{C}$	3.1	4.2	$\text{m}\Omega$
$V_{GE(th)}$	$V_{GE}=V_{CE}, I_C = 8\text{ mA}$	5.1	5.8	6.4	V
I_{CES}	$V_{GE} = 0\text{ V}, V_{CE} = 650\text{ V}, T_j = 25^\circ\text{C}$			0.2	mA
C_{ies}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	18.5		nF
C_{oes}		$f = 1\text{ MHz}$	1.16		nF
C_{res}		$f = 1\text{ MHz}$	0.55		nF
Q_G	$V_{GE} = -15\text{ V} \dots +15\text{ V}$		3023		nC
R_{Gint}	$T_j = 25^\circ\text{C}$		1.0		Ω
$t_{d(on)}$	$V_{CC} = 300\text{ V}$ $I_C = 300\text{ A}$	$T_j = 150^\circ\text{C}$			ns
t_r	$V_{GE} = +15/-15\text{ V}$	$T_j = 150^\circ\text{C}$			ns
E_{on}	$R_{G on} = 2\ \Omega$	$T_j = 150^\circ\text{C}$	5.5		mJ
$t_{d(off)}$	$R_{G off} = 2\ \Omega$	$T_j = 150^\circ\text{C}$			ns
t_f	$di/dt_{on} = 4760\text{ A}/\mu\text{s}$ $di/dt_{off} = 3478\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$			ns
E_{off}		$T_j = 150^\circ\text{C}$	15.6		mJ
$R_{th(j-c)}$	per IGBT			0.16	K/W
$R_{th(c-s)}$	per IGBT ($\lambda_{grease}=0.81\text{ W/mK}$, thickness 50-100 μm)		0.051		K/W
$R_{th(c-s)}$	per IGBT ($\lambda=3.4\text{ W/mK}$)		0.031		K/W



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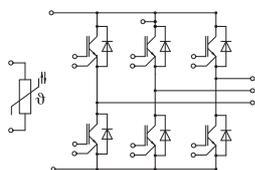
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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
Inverse diode						
$V_F = V_{EC}$	$I_F = 300\text{ A}$ $V_{GE} = 0\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.40	1.76		V
		$T_j = 150^\circ\text{C}$	1.39	1.77		V
V_{F0}	chipelevel	$T_j = 25^\circ\text{C}$	1.04	1.24		V
		$T_j = 150^\circ\text{C}$	0.85	0.99		V
r_F	chipelevel	$T_j = 25^\circ\text{C}$	1.19	1.76		mΩ
		$T_j = 150^\circ\text{C}$	1.79	2.6		mΩ
I_{RRM}	$I_F = 300\text{ A}$	$T_j = 150^\circ\text{C}$	212			A
Q_{rr}	$di/dt_{off} = 4760\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$	21.6			μC
E_{rr}	$V_{GE} = -15\text{ V}$ $V_{CC} = 300\text{ V}$	$T_j = 150^\circ\text{C}$	5.2			mJ
$R_{th(j-c)}$	per diode				0.25	K/W
$R_{th(c-s)}$	per diode ($\lambda_{grease}=0.81\text{ W/mK}$, thickness 50-100μm)			0.047		K/W
$R_{th(c-s)}$	per diode ($\lambda=3.4\text{ W/mK}$)			0.037		K/W
Module						
L_{CE}				20		nH
R_{CC+EE}	measured per switch	$T_C = 25^\circ\text{C}$	1.2			mΩ
		$T_C = 125^\circ\text{C}$	1.65			mΩ
$R_{th(c-s)1}$	calculated without thermal coupling			0.004		K/W
$R_{th(c-s)2}$	including thermal coupling, T_s underneath module ($\lambda_{grease}=0.81\text{ W}/$ (m^2K))			0.0069		K/W
$R_{th(c-s)2}$	including thermal coupling, T_s underneath module, pre-applied phase change material			0.0048		K/W
M_s	to heat sink (M5)		3		6	Nm
M_t		to terminals (M6)	3		6	Nm
						Nm
w				398		g
Temperature Sensor						
R_{100}	$T_c=100^\circ\text{C}$ ($R_{25}=5\text{ k}\Omega$)			$493 \pm 5\%$		Ω
$B_{100/125}$	$R_{(T)}=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]$; $T[\text{K}]$;			3550 $\pm 2\%$		K



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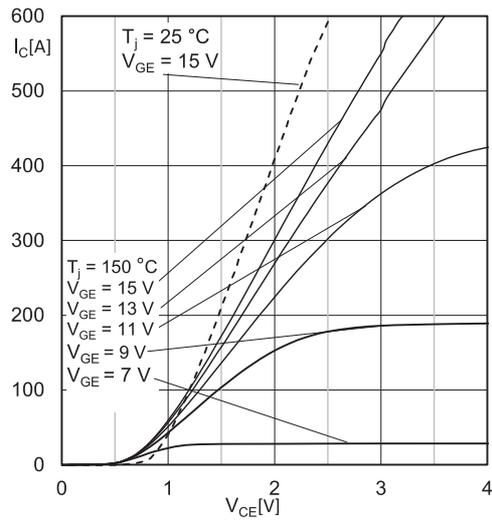


Fig. 1: Typ. output characteristic, inclusive R_{CC}+EE'

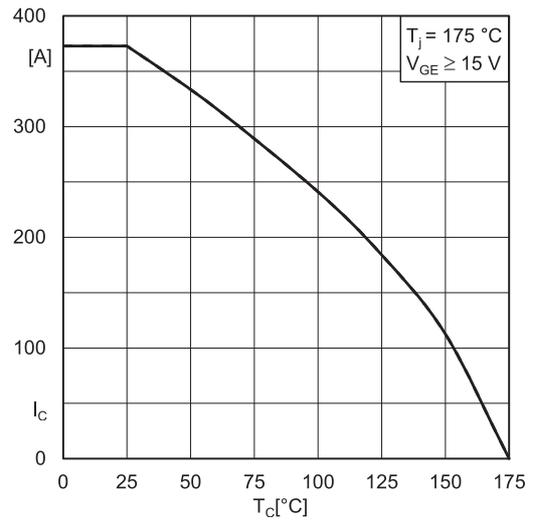


Fig. 2: Rated current vs. temperature I_C = f(T_C)

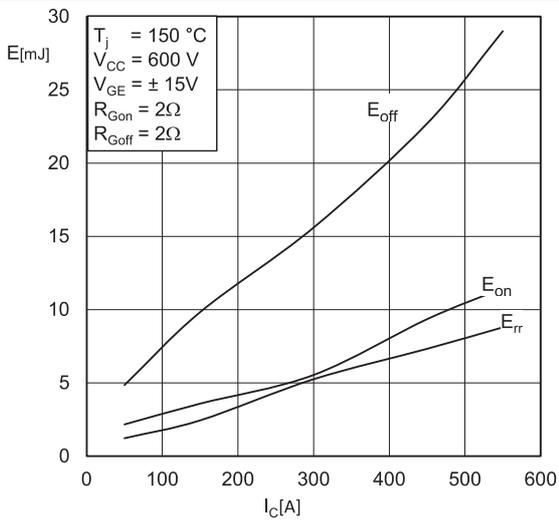


Fig. 3: Typ. turn-on /-off energy = f(I_C)

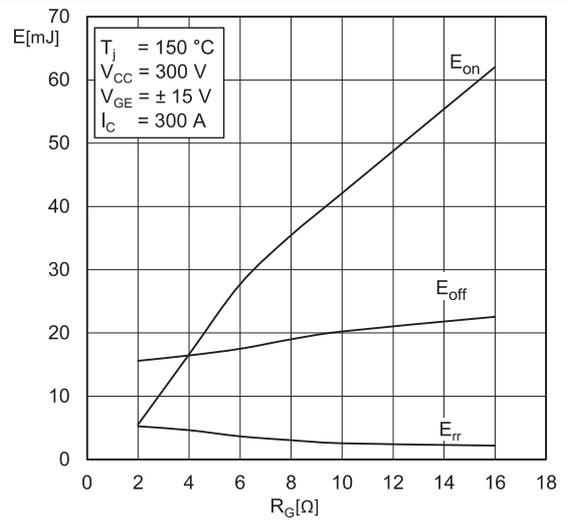


Fig. 4: Typ. turn-on /-off energy = f(R_G)

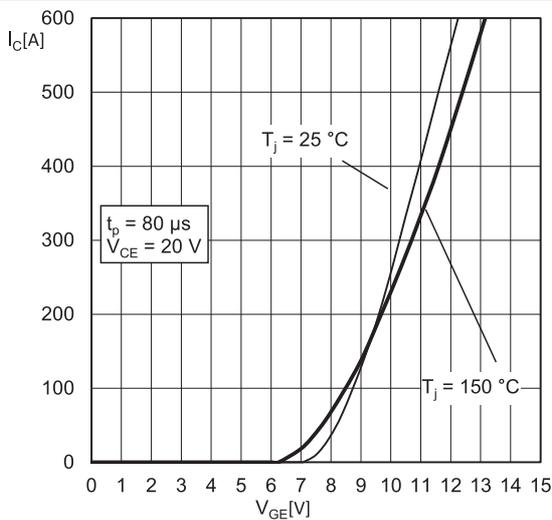


Fig. 5: Typ. transfer characteristic

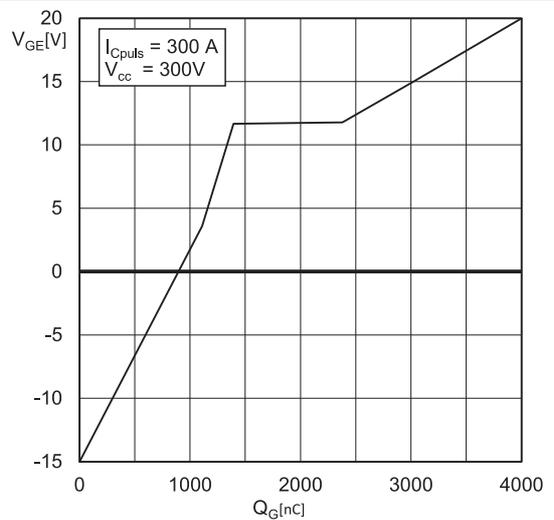


Fig. 6: Typ. gate charge characteristic

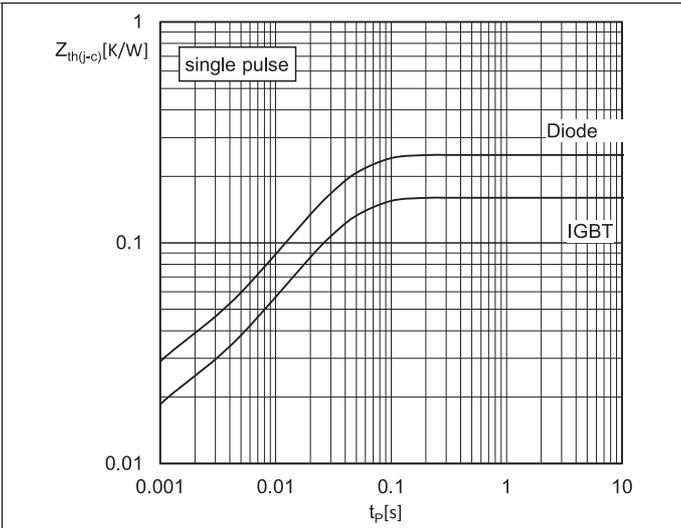


Fig. 9: Transient thermal impedance

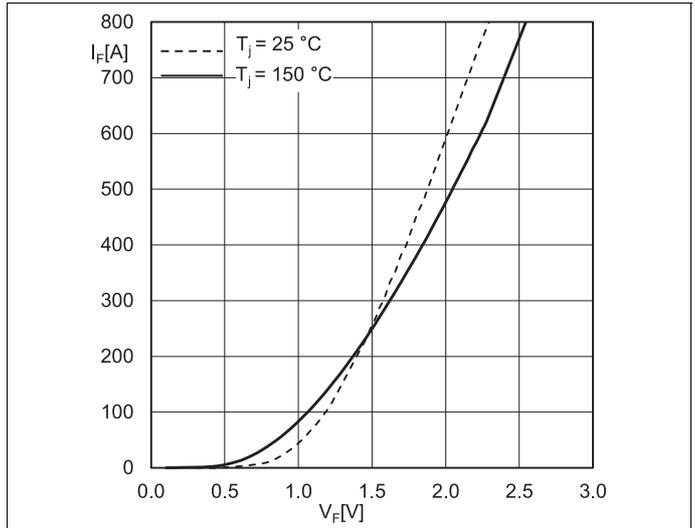
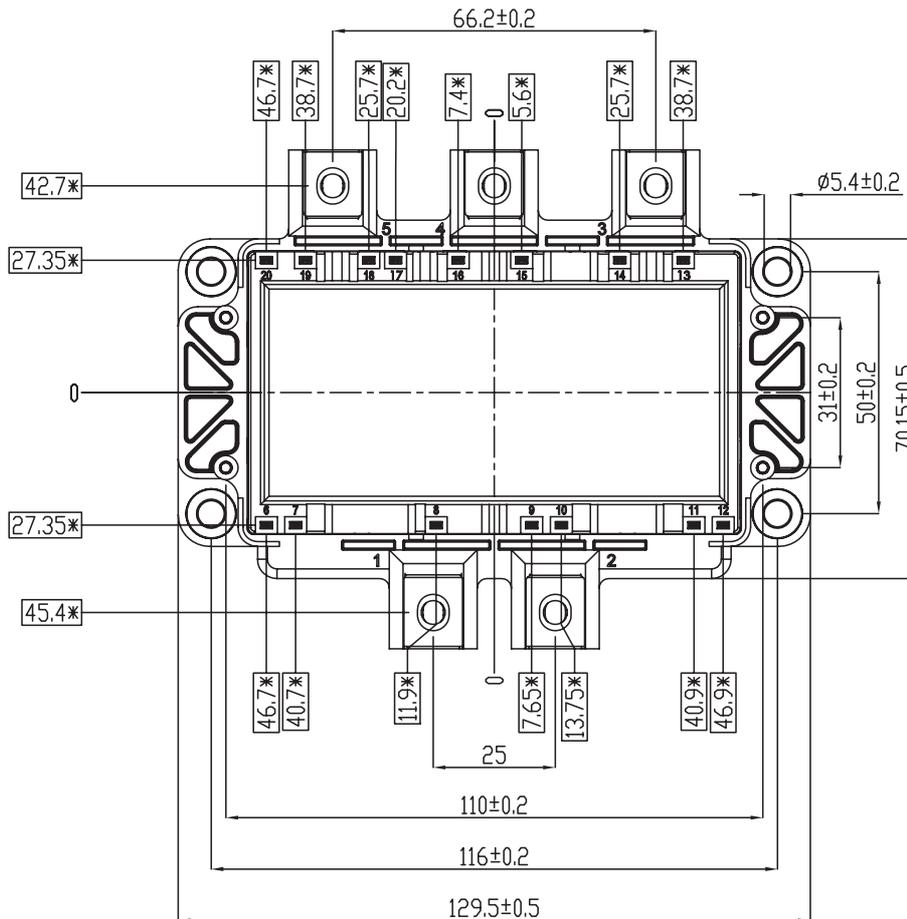
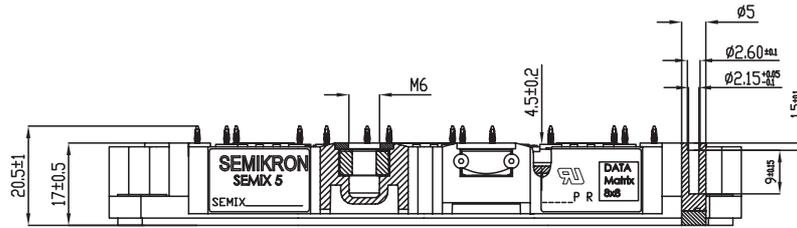


Fig. 10: Typ. CAL diode forward charact., incl. $R_{CC'+EE'}$

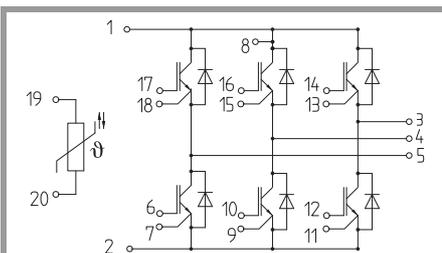
SEMiX305GD07E4



* = All dimension with tolerance of $\begin{matrix} \oplus \\ \ominus \end{matrix} \ 0.4$

For technical details please refer to SEMiX(R)5 Mounting Instruction

SEMiX5p



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This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, chapter IX.

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